## Applicant(s)/Patent Under Reexamination CHOU ET AL. Application/Control No. 10/724,483 Notice of References Cited Examiner Art Unit Page 1 of 1 David E. Graybill 2822

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	. Name	Classification
	Α	US-6,074,908 A	06-2000	Huang, Jenn Ming	438/241
	В	US-6,281,050 B1	08-2001	Sakagami, Eiji	438/142
	C	US-6,314,023 B1	11-2001	Waldo, Whitson	365/185.09
	D	US-2002/0168850 A1	11-2002	Kim, Sung-Hoan	438/637
	Е	US-2003/0073288 A1	04-2003	Pham et al.	438/261
	F	US-2004/0081715 A1	04-2004	Schmitz et al.	424/776
	G	US-6,734,113 B1	05-2004	Cho et al.	438/763
	Н	US-6,780,715 B2	08-2004	Jeong, Yong Sik	438/275
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-	-		

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	P					
	O	•				
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	•
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	x	

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